## Application/Control No. Applicant(s)/Patent Under Reexamination 10/663,714 INOUE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2826 A. Sefer **U.S. PATENT DOCUMENTS** Document Number Date Classification Name · Country Code-Number-Kind Code MM-YYYY US-6,103,543 08-2000 438/46 Uemura et al. Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 11-145518 05-1999 Ν Japan Ito et al JP 9-232680 09-1977 Japan Kamimura et al 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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